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(72) Inventor: **Sera, Kenji**  
**Minato-ku, Tokyo (JP)**

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(74) Representative: **Baronetzky, Klaus, Dipl.-Ing.**  
**Splanemann Reitzner**  
**Baronetzky Westendorp**  
**Patentanwälte**  
**Rumfordstrasse 7**  
**80469 München (DE)**

(71) Applicant: **NEC CORPORATION**  
**Tokyo (JP)**

(54) **Field effect transistor and method of manufacturing the same as well as liquid crystal display using the same as well as method of manufacturing the same**

(57) A gate-overlap-drain structure is obtained by a single pair of a single impurity implantation process and a single laser anneal process, wherein the improved gate-overlap-drain structure includes lightly activated high impurity concentration regions exhibiting substantially the same function as the lightly doped drain re-

gions, wherein the lightly activated high impurity concentration regions are bounded with high impurity concentration regions serving as source and drain regions. The boundaries are self-aligned to edges of a gate electrode. Side regions of the gate electrode overlap the lightly activated high impurity concentration regions.

**FIG. 1A prior art**

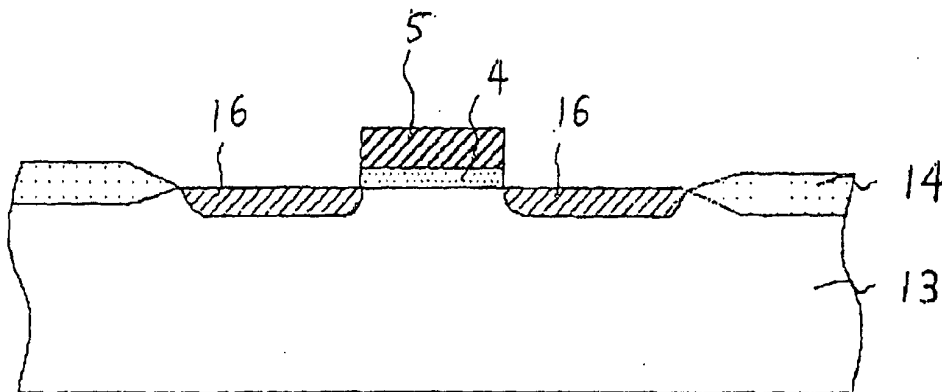


FIG. 1B prior art

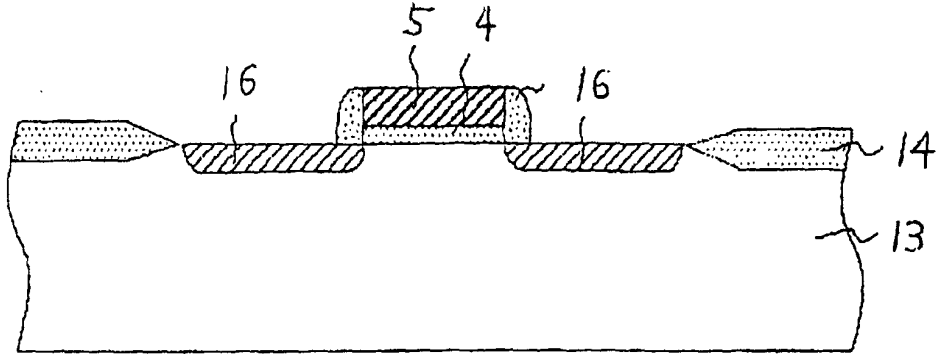
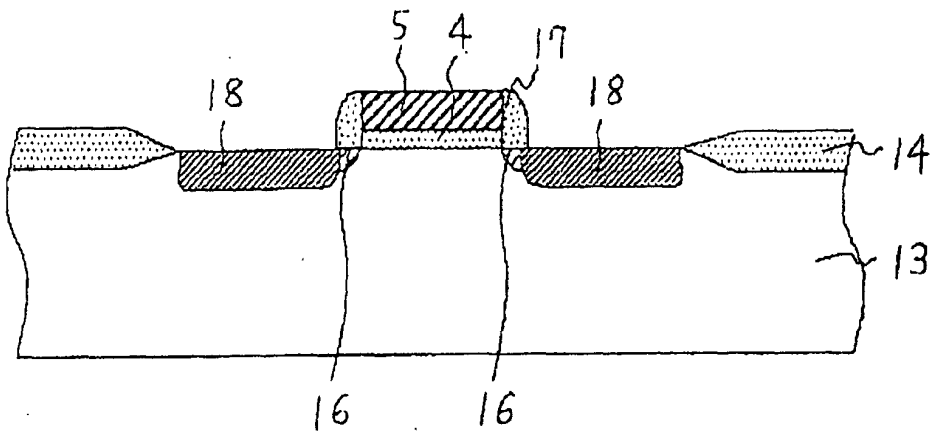


FIG. 1C prior art





European Patent Office

EUROPEAN SEARCH REPORT

Application Number  
EP 02 01 7240

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
X	US 6 001 714 A (GOTO YASUMASA ET AL) 14 December 1999 (1999-12-14) * column 3, line 14 - line 19 * * column 10, line 28 - line 40; figures 9c,14 *	1-30, 38-41	H01L21/268 H01L21/336 H01L29/786
Y	-----	31-37	
X	EP 0 602 250 A (SEIKO EPSON CORP) 22 June 1994 (1994-06-22)  * column 2, line 32 - line 41 * * column 5, line 21 - line 33 * * column 7, line 16 - column 15, line 22; claims; figures *	1-3, 6-10, 13-17, 20-23, 26,38-41	
Y	-----	31-37	
X	EP 1 041 641 A (SEMICONDUCTOR ENERGY LAB) 4 October 2000 (2000-10-04)  * page 5, paragraph 32 - page 12, paragraph 121; figures 1A-5 *	1-3, 6-10, 12-17, 20-23,26	TECHNICAL FIELDS SEARCHED (Int.Cl.7) H01L G02F
Y	US 5 485 019 A (TAKEMURA YASUHIKO ET AL) 16 January 1996 (1996-01-16) * column 7, line 24 - column 8, line 14; figures 4A-D *	1-30	
Y	EP 0 645 802 A (SEMICONDUCTOR ENERGY LAB) 29 March 1995 (1995-03-29) * the whole document *	1-30	
	----- -/--		
The present search report has been drawn up for all claims			
Place of search Berlin		Date of completion of the search 12 November 2004	Examiner Hoffmann, N
CATEGORY OF CITED DOCUMENTS X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document		T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons ----- & : member of the same patent family, corresponding document	

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European Patent Office

EUROPEAN SEARCH REPORT

Application Number  
EP 02 01 7240

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
X	TSUKAMOTO H ET AL: "Selective laser annealing (SELA) used in the fabrication of sub-0.1 μm MOSFETs" SOLID STATE ELECTRONICS, ELSEVIER SCIENCE PUBLISHERS, BARKING, GB, vol. 42, no. 4, 1 April 1998 (1998-04-01), pages 547-556, XP004116483 ISSN: 0038-1101 * the whole document *	1-30	
X	OHGATA K ET AL: "A new dopant activation technique for poly-Si TFTs with a self-aligned gate-overlapped LDD structure" IEDM 2000, 10 December 2000 (2000-12-10), pages 205-208, XP010531745 * the whole document *	1-3, 6-10, 12-17, 20-23,26	
A	PATENT ABSTRACTS OF JAPAN vol. 0180, no. 08 (E-1486), 7 January 1994 (1994-01-07) -& JP 05 251465 A (FUJI XEROX CO LTD), 28 September 1993 (1993-09-28) * abstract *	1-41	
A	US 6 028 326 A (TAKEMURA YASUHIKO ET AL) 22 February 2000 (2000-02-22) * page 2, line 2 - line 13 *	1-41	
The present search report has been drawn up for all claims			
Place of search Berlin		Date of completion of the search 12 November 2004	Examiner Hoffmann, N
CATEGORY OF CITED DOCUMENTS X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document		T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons ..... & : member of the same patent family, corresponding document	

EPC FORM 1505 03/02 (P04001)

**ANNEX TO THE EUROPEAN SEARCH REPORT  
ON EUROPEAN PATENT APPLICATION NO.**

EP 02 01 7240

This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report. The members are as contained in the European Patent Office EDP file on  
The European Patent Office is in no way liable for these particulars which are merely given for the purpose of information.

12-11-2004

Patent document cited in search report		Publication date	Patent family member(s)	Publication date
US 6001714	A	14-12-1999	JP 3305961 B2	24-07-2002
			JP 10104659 A	24-04-1998
			KR 250851 B1	01-05-2000
-----				
EP 0602250	A	22-06-1994	DE 69326123 D1	30-09-1999
			DE 69326123 T2	23-12-1999
			EP 0602250 A1	22-06-1994
			WO 9400882 A1	06-01-1994
			JP 11330487 A	30-11-1999
			US 5508216 A	16-04-1996
			US 5757048 A	26-05-1998
-----				
EP 1041641	A	04-10-2000	CN 1276622 A	13-12-2000
			EP 1041641 A2	04-10-2000
			JP 2000349298 A	15-12-2000
			TW 469484 B	21-12-2001
-----				
US 5485019	A	16-01-1996	JP 6224432 A	12-08-1994
			CN 1305227 A	25-07-2001
			CN 1479137 A	03-03-2004
			CN 1070052 A ,B	17-03-1993
			KR 9702004 B1	20-02-1997
			KR 9608133 B1	20-06-1996
			KR 9611185 B1	21-08-1996
			TW 476451 Y	11-02-2002
			TW 540828 Y	01-07-2003
			US 6147375 A	14-11-2000
			US 5521107 A	28-05-1996
			US 6566711 B1	20-05-2003
			US 2003173570 A1	18-09-2003
			US 5849611 A	15-12-1998
			US 6013928 A	11-01-2000
			US 6476447 B1	05-11-2002
-----				
EP 0645802	A	29-03-1995	JP 2759414 B2	28-05-1998
			JP 7135213 A	23-05-1995
			CN 1109220 A ,B	27-09-1995
			EP 0645802 A2	29-03-1995
			JP 3212060 B2	25-09-2001
			JP 7169974 A	04-07-1995
			JP 2000150907 A	30-05-2000
			JP 2002033328 A	31-01-2002
			JP 2002033329 A	31-01-2002
			US 2003100152 A1	29-05-2003
			US 6049092 A	11-04-2000
			JP 2805590 B2	30-09-1998

**ANNEX TO THE EUROPEAN SEARCH REPORT  
ON EUROPEAN PATENT APPLICATION NO.**

EP 02 01 7240

This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report.  
The members are as contained in the European Patent Office EDP file on  
The European Patent Office is in no way liable for these particulars which are merely given for the purpose of information.

12-11-2004

Patent document cited in search report		Publication date	Patent family member(s)	Publication date
EP 0645802	A		JP 7169975 A	04-07-1995
			JP 2840812 B2	24-12-1998
			JP 7218932 A	18-08-1995
-----				
JP 05251465	A	28-09-1993	NONE	
-----				
US 6028326	A	22-02-2000	JP 3535205 B2	07-06-2004
			JP 6333951 A	02-12-1994
			JP 3535463 B2	07-06-2004
			JP 2001244475 A	07-09-2001
			JP 3535465 B2	07-06-2004
			JP 2001250960 A	14-09-2001
			US 2001053613 A1	20-12-2001
			US 5946560 A	31-08-1999
-----				

专利名称(译)	场效应晶体管及其制造方法以及使用该场效应晶体管的液晶显示器及其制造方法		
公开(公告)号	<a href="#">EP1282173A3</a>	公开(公告)日	2005-01-12
申请号	EP2002017240	申请日	2002-07-31
申请(专利权)人(译)	NEC公司		
当前申请(专利权)人(译)	GETNER FOUNDATION LLC		
[标]发明人	SERA KENJI		
发明人	SERA, KENJI		
IPC分类号	G02F1/1368 H01L21/268 H01L21/336 H01L29/417 H01L29/78 H01L29/786		
CPC分类号	H01L29/66757 H01L21/268 H01L29/41733 H01L29/4908 H01L29/78621 H01L29/78627 H01L29/78666 H01L2029/7863		
优先权	2001233256 2001-08-01 JP		
其他公开文献	EP1282173A2		
外部链接	<a href="#">Espacenet</a>		

摘要(译)

通过单对单杂质注入工艺和单激光退火工艺获得栅极 - 重叠 - 漏极结构，其中改进的栅极 - 重叠 - 漏极结构包括轻微激活的高杂质浓度区域，其显示出与轻微相同的功能。掺杂漏极区域，其中轻微激活的高杂质浓度区域与用作源极和漏极区域的高杂质浓度区域界定。边界与栅电极的边缘自对准。栅电极的侧区与轻微激活的高杂质浓度区重叠。

FIG. 1A prior art

